

## EDXRF spectra

The EDXRF spectra (Fig. S3) and quantitative analysis (the results are listed in Table S2) of the t-Ni system reveals the presence of major (Ni and Pd) and minor elements (Cr, Mn and Fe). In the preliminary study the Pd concentration was determined with Pd L $\alpha$  line and Rh target X-ray tube operated at maximum voltage of 30 keV. The determined concentration of Pd (2.3 %) was much higher than the expected value (1.0%). It can be explained by the low energy of L $\alpha$  line and the low information depth  $d_{99\%}$  of ca 4  $\mu\text{m}$  (see Table 1). In consequence, the Pd concentration is overestimated because Pd nanoparticles are located onto the surface of Ni particles. The reliable bulk composition can be obtained with Pd K $\alpha$  line because of much higher energy and, in consequence, a much larger penetration range of X-rays compared to Pd L $\alpha$  line ( $d_{99\%} = 60\text{--}85 \mu\text{m}$ ). This time, the determined Pd concentration is close to the expected value. It should be noted here that the Pd/Ni catalysts have very similar bulk composition before and after use.

**Table S2.** EDXRF analysis of nano-Pd/Ni catalyst (t-Ni) before (BR) and after reaction (AR). Results in % m/m.

Element	Pd L $\alpha$ line; $d_{99\%} = 4 \mu\text{m}^a$		Pd K $\alpha$ line; $d_{99\%} = 60\text{--}85 \mu\text{m}$	
	BR	AR	BR	AR
Pd	$2.43 \pm 0.11$	$2.31 \pm 0.14$	$1.23 \pm 0.05$	$1.05 \pm 0.04$
Ca	$2.13 \pm 0.14$	$2.04 \pm 0.18$	$2.21 \pm 0.23$	$2.09 \pm 0.26$
Cr	$0.27 \pm 0.05$	$0.40 \pm 0.04$	$0.37 \pm 0.02$	$0.36 \pm 0.02$
Mn	$0.055 \pm 0.007$	$0.068 \pm 0.006$	$0.074 \pm 0.004$	$0.076 \pm 0.005$
Fe	$2.41 \pm 0.10$	$2.46 \pm 0.10$	$2.52 \pm 0.08$	$2.41 \pm 0.09$
Ni	$92.7 \pm 1.9$	$92.7 \pm 2.2$	$93.6 \pm 1.5$	$94.0 \pm 2.0$

<sup>a</sup> the information depth  $d_{99\%}$  for element i that would yield 99% of the element intensity is given by the formula  $d_{99\%} = 4.6 / \chi(E_0, E_i) \times \rho$ , where  $\rho$  is the density of the sample and  $\chi(E_0, E_i) = \mu(E_0) \csc(\phi_1) + \mu(E_i) \csc(\phi_2)$  is total mass-attenuation coefficient of the sample.  $\mu(E_0)$  and  $\mu(E_i)$  represent the mass attenuation coefficients of the sample at the primary  $E_0$  and fluorescent radiation  $E_i$  (Pd L $\alpha$  or Pd K $\alpha$  line at 2.84 and 19.28 keV, respectively),  $\phi_1$  and  $\phi_2$  are the incidence and take-off angles, respectively.